

<b><i>Search Notes</i></b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	<b>Examiner</b>	<b>Art Unit</b>

<b>SEARCHED</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>

<b>SEARCH NOTES</b>		
<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
East databases searched- USPAT, PGPUB, EPO, JPO, Derwent	8/4/09	MM
STN databases- Caplus, Scisearch, Medline	8/4/09	MM
Inventor search	8/4/09	MM

<b>INTERFERENCE SEARCH</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>

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